

## Vishay Siliconix

SPECIFICATIONS (T <sub>J</sub> = 25 °C, unless otherwise noted)											
PARAMETER	SYMBOL	TEST CONDITIONS	MIN.	TYP.	MAX.	UNIT					
Static											
Drain-Source Breakdown Voltage	$V_{DS}$	$V_{GS} = 0 \text{ V}, I_D = -250 \mu\text{A}$	-20	-	-	V					
V <sub>DS</sub> Temperature Coefficient	$\Delta V_{DS}/T_{J}$	I <sub>D</sub> = -250 μA	-	-12	-	mV/°C					
GS(th) Temperature Coefficient ΔV <sub>GS(th)</sub>		I <sub>D</sub> = -230 μA	-	2.5	-	IIIV/ C					
Gate-Source Threshold Voltage	V <sub>GS(th)</sub>	$V_{DS} = V_{GS}$ , $I_D = -250 \mu A$	-0.4	-	-1	V					
Gate-Source Leakage	I <sub>GSS</sub>	$V_{DS} = 0 \text{ V}, V_{GS} = \pm 8 \text{ V}$ -		-	± 100	nA					
Zero Gate Voltage Drain Current	I <sub>DSS</sub>	$V_{DS} = -20 \text{ V}, V_{GS} = 0 \text{ V}$	-	-	-1	μΑ					
		$V_{DS} = -20 \text{ V}, V_{GS} = 0 \text{ V}, T_{J} = 70 \text{ °C}$	-	-	-10						
On-State Drain Current <sup>a</sup>	I <sub>D(on)</sub>	$V_{DS} \le -5 \text{ V}, V_{GS} = -4.5 \text{ V}$	-10	-	=	Α					
Drain-Source On-State Resistance <sup>a</sup>		$V_{GS} = -4.5 \text{ V}, I_D = -1.5 \text{ A}$	-	0.083	0.100						
	В	$V_{GS} = -2.5 \text{ V}, I_D = -1.5 \text{ A}$	-	0.098	0.118	Ω					
	R <sub>DS(on)</sub>	V <sub>GS</sub> = -1.8 V, I <sub>D</sub> = -1 A	-	0.115	0.140						
		V <sub>GS</sub> = -1.5 V, I <sub>D</sub> = -0.5 A	-	0.136	0.205	7					
Forward Transconductance <sup>a</sup>	9 <sub>fs</sub>	V <sub>DS</sub> = -10 V, I <sub>D</sub> = -1 A	-	7	-	S					
Dynamic <sup>b</sup>				•							
Input Capacitance	C <sub>iss</sub>		-	610	-	pF					
Output Capacitance	C <sub>oss</sub>	$V_{DS} = -10 \text{ V}, V_{GS} = 0 \text{ V}, f = 1 \text{ MHz}$	-	120	-						
Reverse Transfer Capacitance	C <sub>rss</sub>		-	95	-						
Total Gate Charge	$Q_g$	V <sub>DS</sub> = -10 V, V <sub>GS</sub> = -8 V, I <sub>D</sub> = 1 A	-	16	24	nC					
			-	9.5	15						
Gate-Source Charge	$Q_{gs}$	$V_{DS} = -10 \text{ V}, V_{GS} = -4.5 \text{ V}, I_{D} = 1 \text{ A}$	-	0.9	-						
Gate-Drain Charge	Q <sub>gd</sub>		-	2.6	-						
Gate Resistance	$R_g$	V <sub>GS</sub> = -0.1 V, f = 1 MHz	-	6.5	-	Ω					
Turn-On Delay Time	t <sub>d(on)</sub>		-	15	25	ns					
Rise Time	t <sub>r</sub>	$V_{DD}$ = -10 V, $R_L$ = 10 $\Omega$	-	25	40						
Turn-Off Delay Time	t <sub>d(off)</sub>	$I_D\cong$ -1 A, $V_{GEN}=$ -4.5 V, $R_g=$ 1 $\Omega$	-	35	55						
Fall Time	t <sub>f</sub>		-	10	15						
Turn-On Delay Time	t <sub>d(on)</sub>		-	7	15						
Rise Time	t <sub>r</sub>	$V_{DD}$ = -10 V, $R_L$ = 10 $\Omega$	-	12	20						
Turn-Off Delay Time	t <sub>d(off)</sub>	$I_D \cong -1$ A, $V_{GEN} = -8$ V, $R_g = 1$ $\Omega$	-	32	50						
Fall Time	t <sub>f</sub>		-	12	20						
Drain-Source Body Diode Characteris	stics										
Continuous Source-Drain Diode Current	I <sub>S</sub>	T <sub>A</sub> = 25 °C	-	-	-1.5	А					
Pulse Diode Forward Current	I <sub>SM</sub>		-	-	-20						
Body Diode Voltage	V <sub>SD</sub>	I <sub>S</sub> = -1 A, V <sub>GS</sub> = 0 V	-	-0.8	-1.2	V					
Body Diode Reverse Recovery Time	t <sub>rr</sub>		-	15	30	ns					
Body Diode Reverse Recovery Charge	Q <sub>rr</sub>		-	10	20	nC					
Reverse Recovery Fall Time	t <sub>a</sub>	$I_F = -1 \text{ A, dI/dt} = 100 \text{ A/}\mu\text{s, T}_J = 25 ^{\circ}\text{C}$	-	9	-	ns					
Reverse Recovery Rise Time	t <sub>b</sub>		-	6	-						

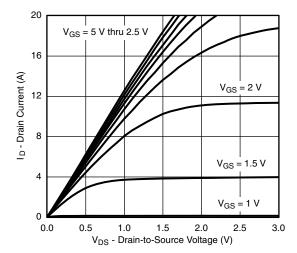
#### Notes

- a. Pulse test; pulse width  $\leq$  300  $\mu$ s, duty cycle  $\leq$  2 %.
- b. Guaranteed by design, not subject to production testing.

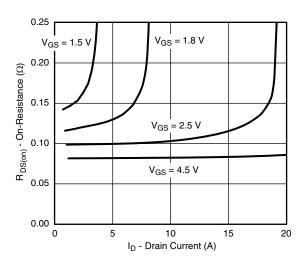
Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.



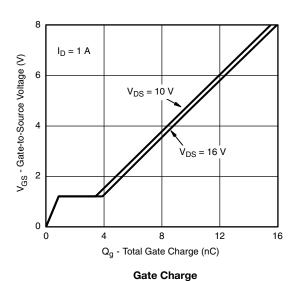
## TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)

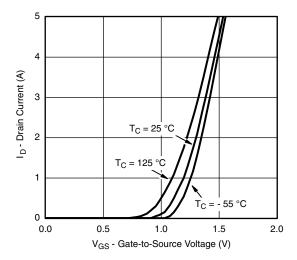


#### **Output Characteristics**

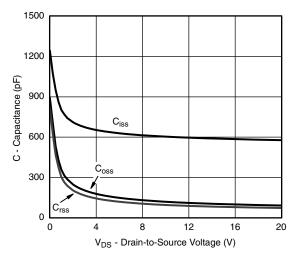


On-Resistance vs. Drain Current and Gate Voltage

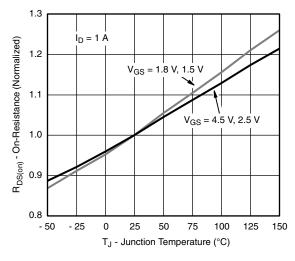




**Transfer Characteristics** 



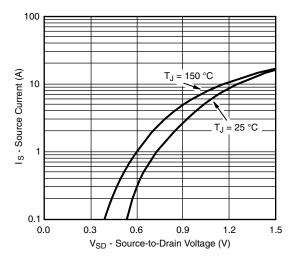
Capacitance



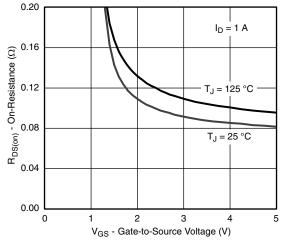
On-Resistance vs. Junction Temperature



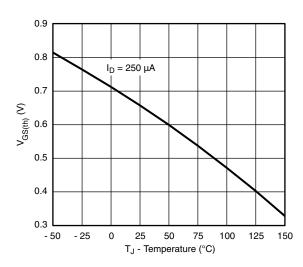
## TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)



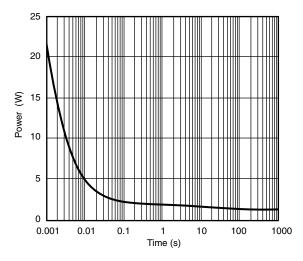
#### Source-Drain Diode Forward Voltage



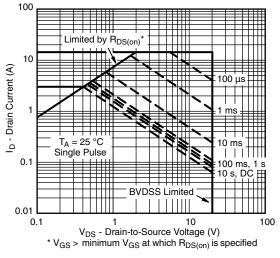
On-Resistance vs. Gate-to-Source Voltage



**Threshold Voltage** 



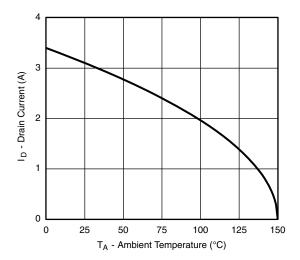
Single Pulse Power, Junction-to-Ambient

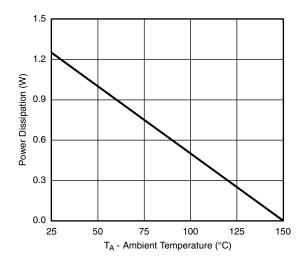


Safe Operating Area, Junction-to-Ambient

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## TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)





**Power Derating** 

#### Current Derating a

#### Note

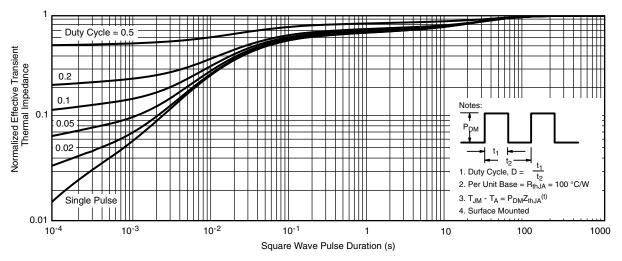
• When mounted on 1" x 1" FR4 with full copper.

#### Note

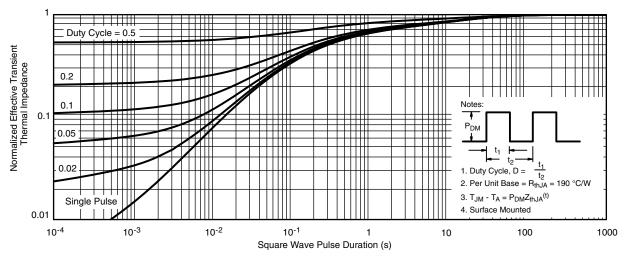
a. The power dissipation P<sub>D</sub> is based on T<sub>J</sub> (max.) = 150 °C, using junction-to-case thermal resistance, and is more useful in settling the upper dissipation limit for cases where additional heatsinking is used. It is used to determine the current rating, when this rating falls below the package limit.



## TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)



Normalized Thermal Transient Impedance, Junction-to-Ambient (1" x 1" FR4 Board with Full Copper)



Normalized Thermal Transient Impedance, Junction-to-Ambient (1" x 1" FR4 Board with Minimum Copper)

Vishay Siliconix maintains worldwide manufacturing capability. Products may be manufactured at one of several qualified locations. Reliability data for Silicon Technology and Package Reliability represent a composite of all qualified locations. For related documents such as package/tape drawings, part marking, and reliability data, see <a href="https://www.vishay.com/ppg?65001">www.vishay.com/ppg?65001</a>.

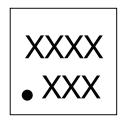


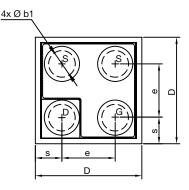
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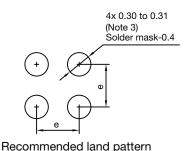
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# MICRO FOOT®: 4-Bumps (1 mm x 1 mm, 0.5 mm Pitch, 0.286 mm Bump Height)

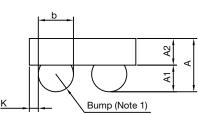
Mark on backside of die

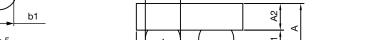












#### Notes

- 1. Bumps are 95.5/3.8/0.7 Sn/Ag/Cu.
- 2. Backside surface is coated with a Ti/Ni/Ag layer.
- 3. Non-solder mask defined copper landing pad.
- 4. Laser mark on the backside surface of die.
- 5. "b1" is the diameter of the solderable substrate surface, defined by an opening in the solder resist layer solder mask defined.
- 6. is the location of pin 1

DIM.		MILLIMETERS		INCHES				
	MIN.	NOM.	MAX.	MIN.	NOM.	MAX.		
Α	0.458	0.504	0.550	0.0180	0.0198	0.0217		
A1	0.214	0.250	0.286	0.0084	0.0098	0.0113		
A2	0.244	0.254	0.264	0.0096	0.0100	0.0104		
b	0.297	0.330	0.363	0.0117	0.0130	0.0143		
b1	0.250			0.0098				
е		0.500			0.0197			
S	0.210	0.230	0.250	0.0083	0.0091	0.0096		
D	0.920	0.960	1.000	0.0362	0.0378	0.0394		
K	0.029	0.065	0.102	0.0011	0.0026	0.0040		

#### Note

• Use millimeters as the primary measurement.

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